

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/708,947	CHEN ET AL.	
Examiner	Art Unit	
Gonal C. Ray	2111	

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	SEARCHED				
Class	Subclass	Date	Examiner		
710	8,305,313- 317,105,7 1,72	1/26/2006	GCR		
709	227,250	1/26/2006	GCR		
709	253	1/26/2006	GCR		
340	825,2.1	1/26/2006	GCR		
713	300	1/26/2006	GCR		
361	683,686	1/26/2006	GCR		
379	242,270	1/26/2006	GCR		
379	335	1/26/2006	GCR		
370	257,351	1/26/2006	GCR		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	1/31/2006	GCR		
WEST: US PGPUB, USPT, US OCR, EPO ABS, JPO ABS, DWPI, IBM TDB (see search history printouts)	1/26/2006	GCR		
EAST: USPT (see search history printouts)	1/26/2006	GCR		
NPL: IEEE Xplore (see search history printouts)	1/26/2006	GCR		